

Notic of References Cited

Application/Control No.

10/055,270

Applicant(s)/Patent Under
Reexamination
JOO ET AL.

Examiner

Anh D. Mai

Art Unit

2814

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6204203	03-2001	Narwanka et al.	438/785
	B	US-6303952	10-2001	Aoki et al.	257/295
	C	US-Pub. 2002/0037630	03-2002	Agarwal et al.	438/430
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	I.K. Yoo et al., Leakage Current Mechanism and Accelerated Unified Test of Lead Ziconate Titanate Thin Film Capacitors. IEEE 1992, pp. 225-228.
	V	I. Chung et al., Fabrication of Ferroelectric Capacitors Using RuO ₂ /Pt Electrode. IEEE 1996, pp. 93-101.
	W	G.J. Norga et al. Effect of Crystallisation on Fatigue in Sol-Gel PZT Ferroelectric Capacitors with Reactively Sputtered RuO ₂ Electrode Layers. IEEE 1998, pp. 3-6.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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